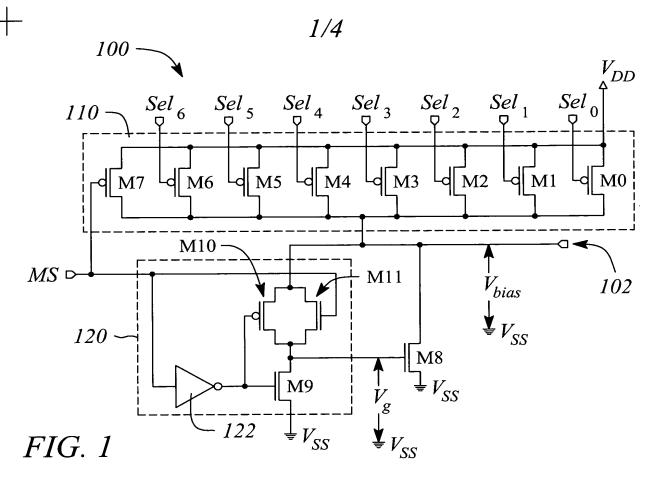
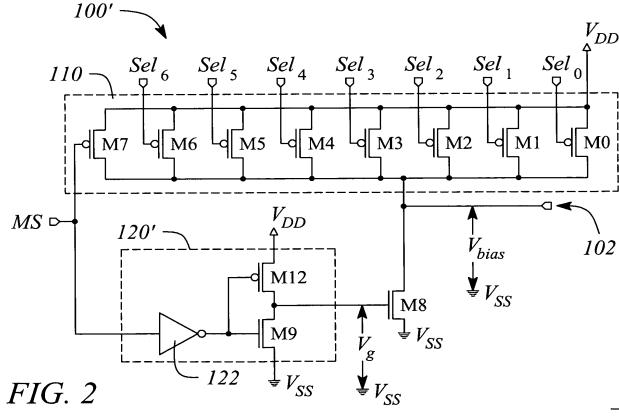
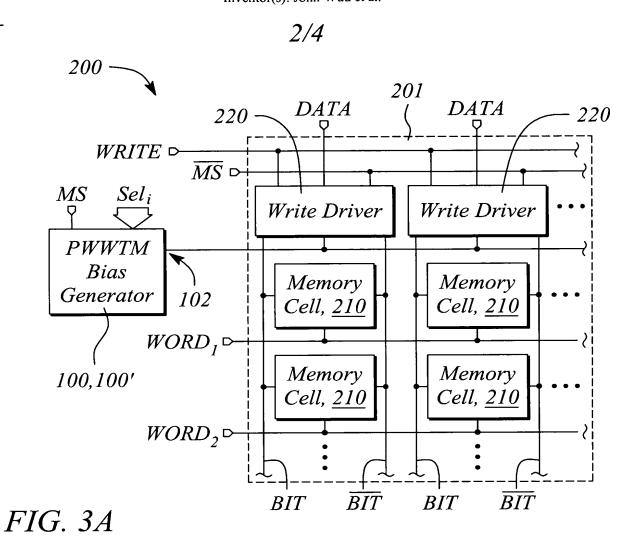
Hewlett-Packard Company Attorney Docket No. 200207084-1 Title: "Programmable Weak Write Test Mode (PWWTM) Bias Generation Having Logic High Output Default Mode"

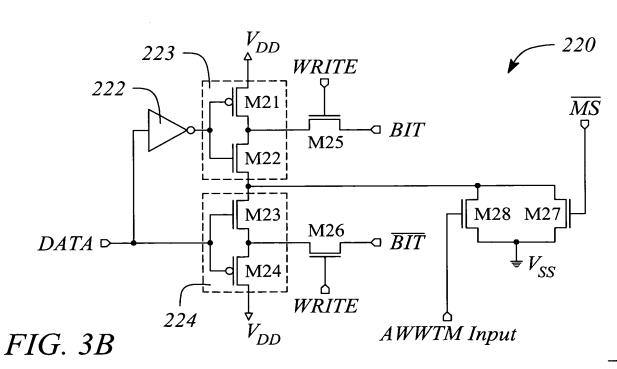
Bias Generation Having Logic High Output Def Inventor(s): John Wuu et al.





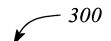
Hewlett-Packard Company
Attorney Docket No. 200207084-1
Title: "Programmable Weak Write Test Mode (PWWTM)
Bias Generation Having Logic High Output Default Mode"
Inventor(s): John Wuu et al.

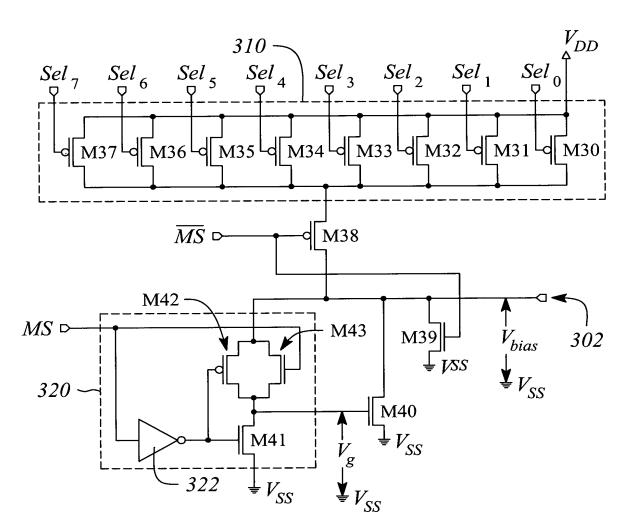




Hewlett-Packard Company
Attorney Docket No. 200207084-1
Title: "Programmable Weak Write Test Mode (PWWTM)
Bias Generation Having Logic High Output Default Mode"
Inventor(s): John Wuu et al.

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Prior Art

FIG. 4

Hewlett-Packard Company
Attorney Docket No. 200207084-1
Title: "Programmable Weak Write Test Mode (PWWTM)
Bias Generation Having Logic High Output Default Mode"
Inventor(s): John Wuu et al.

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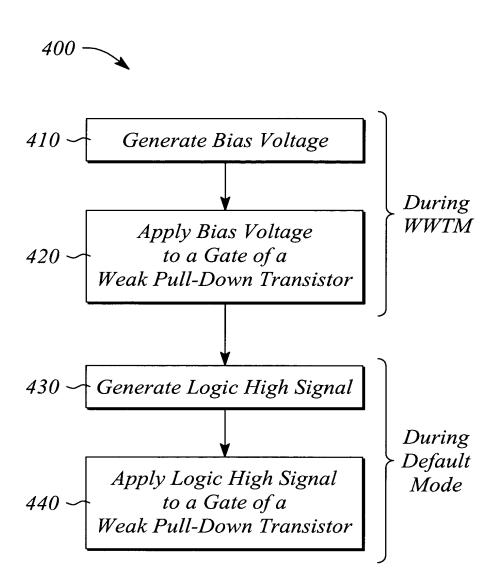


FIG. 5